

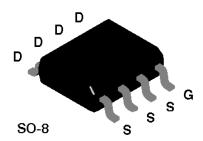
# NDS8426 Single N-Channel Enhancement Mode Field Effect Transistor

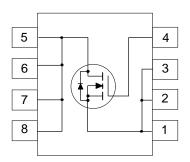
### **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

#### **Features**

- 9.9 A, 20 V.  $R_{DS(ON)} = 0.015 \Omega$  @  $V_{GS} = 4.5 \text{ V}$ .  $R_{DS(ON)} = 0.020 \Omega$  @  $V_{GS} = 2.7 \text{ V}$ .
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- High power and current handling capability in a widely used surface mount package.





## **ABSOLUTE MAXIMUM RATINGS** $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		NDS8426	Units
V <sub>DSS</sub>	Drain-Source Voltage		20	V
$V_{GSS}$	Gate-Source Voltage		8	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	9.9	А
	- Pulsed		20	
$P_{D}$	Maximum Power Dissipation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
$\Gamma_{\rm J}, T_{ m STG}$	Operating and Storage Temperature Range		-55 to 150	က
THERMA	L CHARACTERISTICS			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambie	nt (Note 1a)	50	°C/W
R <sub>euc</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	25	°CW

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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS	·					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		20			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V}, \ V_{GS} = 0 \text{ V}$				1	μΑ
			T <sub>J</sub> =55°C			10	μΑ
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = 8 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate - Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHAR	ACTERISTICS (Note 2)						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		0.4	0.6	1	V
			T <sub>J</sub> = 125°C	0.3	0.34	0.8	Ī
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 9.9 \text{ A}$			0.013	0.015	Ω
			T <sub>J</sub> = 125°C		0.017	0.027	Î
		$V_{GS} = 2.7 \text{ V}, I_D = 8.8 \text{ A}$			0.016	0.02	Ī
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		20			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 9.9 \text{ A}$			38		S
DYNAMIC	CHARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			1765		pF
C <sub>oss</sub>	Output Capacitance				940		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				360		pF
SWITCHI	NG CHARACTERISTICS (Note 2)						
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DD} = 5 \text{ V}, \ I_{D} = 1 \text{ A},$ $V_{GEN} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$			15	30	ns
t,	Turn - On Rise Time				30	55	ns
$\mathbf{t}_{D(off)}$	Turn - Off Delay Time				120	220	ns
t,	Turn - Off Fall Time				58	100	ns
$Q_g$	Total Gate Charge	$V_{DS} = 10 \text{ V},$ $I_{D} = 9.9 \text{ A}, V_{GS} = 4.5 \text{ V}$			46	64	nC
$Q_{gs}$	Gate-Source Charge				3		nC
$Q_{gd}$	Gate-Drain Charge				18		nC

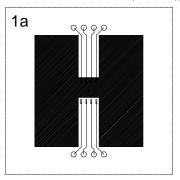
ELECTRICAL CHARACTERISTICS (T <sub>A</sub> = 25°C unless otherwise noted)								
Symbol	Parameter	Conditions	Min	Тур	Max	Units		
DRAIN-SOURCE DIODE CHARACTERISTICS								
Is	Continuous Source Diode Current				2.1	Α		
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \ I_S = 2.1 \text{ A} \ \text{(Note 2)}$		0.65	1.2	V		

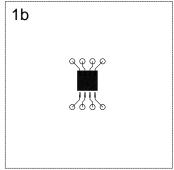
1. R<sub>NA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>NC</sub> is guaranteed by design while  $\boldsymbol{R}_{\theta\text{CA}}$  is determined by the user's board design.

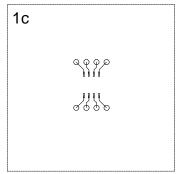
$$P_D(t) = \frac{T_J - T_A}{R_{\theta J A}(t)} = \frac{T_J - T_A}{R_{\theta J C} + R_{\theta C A}(t)}$$

$$\begin{split} P_D(t) &= \frac{T_J - T_A}{R_{BJA}(t)} = \frac{T_J - T_A}{R_{BJC} + R_{BCB}(t)} \\ \text{Typical R}_{BJA} \text{ using the board layouts shown below on 4.5"x5" FR-4 PCB in a still air environment:} \end{split}$$

- a. 50°C/W when mounted on a 1 in² pad of 2oz copper.
- b. 105°C/W when mounted on a 0.04 in² pad of 2oz copper.
- c. 125°C/W when mounted on a 0.006 in² pad of 2oz copper.







Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  2.0%.

# **Typical Electrical Characteristics**

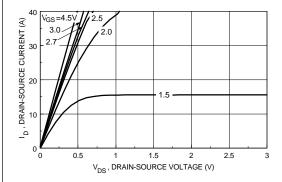


Figure 1. On-Region Characteristics.

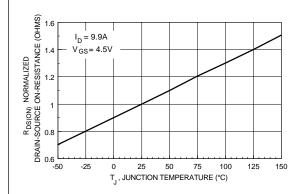


Figure 3. On-Resistance Variation with Temperature.

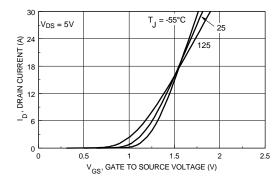


Figure 5. Transfer Characteristics.

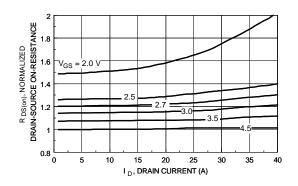


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

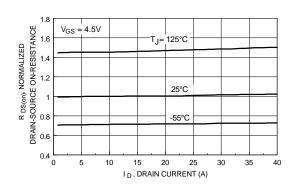


Figure 4. On-Resistance Variation with Drain Current and Temperature.

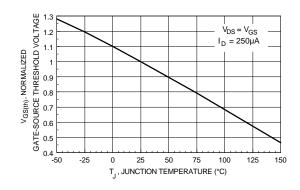


Figure 6. Gate Threshold Variation with Temperature.

# **Typical Electrical Characteristics** (continued)

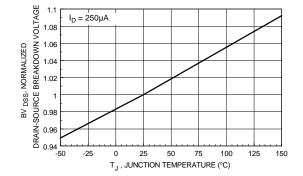


Figure 7. Breakdown Voltage Variation with Temperature.

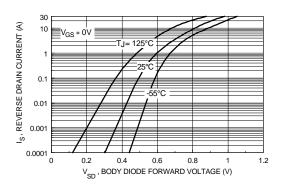


Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature.

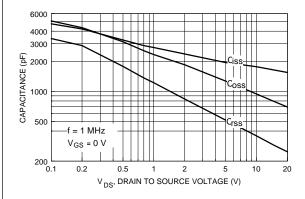


Figure 9. Capacitance Characteristics.

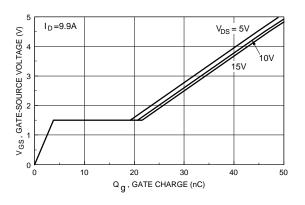


Figure 10. Gate Charge Characteristics.

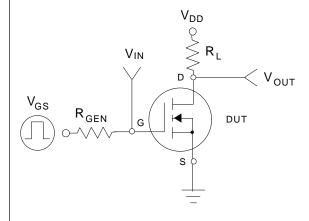


Figure 11. Switching Test Circuit.

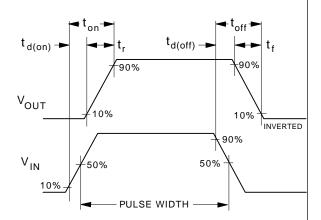
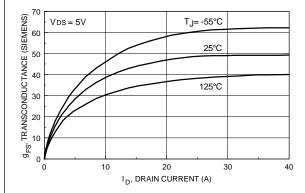


Figure 12. Switching Waveforms.

# Typical Electrical and Thermal Characteristics (continued)

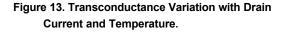


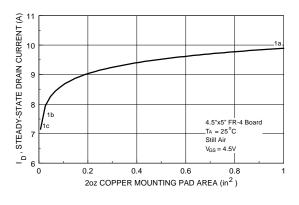
20z COPPER MOUNTING PAD AREA (in 2)

Figure 14. SO-8 Maximum Steady-State Power

0.4

0.2





Dissipation versus Copper Mounting Pad Area.

0.6

4.5"x5" FR-4 Board T<sub>A</sub> = 25° C Still Air

0.8

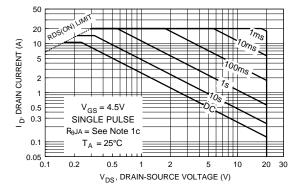


Figure 15. Maximum Steady-State Drain Current versus Copper Mounting Pad Area.

Figure 16. Maximum Safe Operating Area.

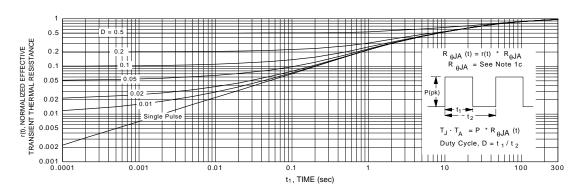


Figure 17. Transient Thermal Response Curve.

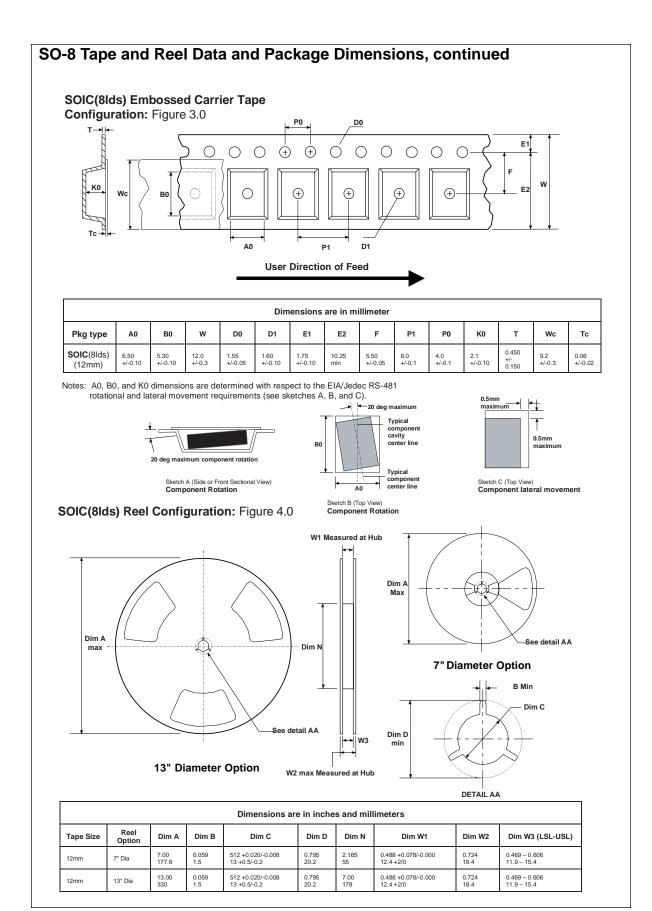
Note: Thermal characterization performed using the conditions described in note 1c. Transient thermal response will change depending on the circuit board design.

2.5

STEADY-STATE POWER DISSIPATION (W)

#### SO-8 Tape and Reel Data and Package Dimensions FAIRCHILD SEMICONDUCTOR IM SOIC(8lds) Packaging Configuration: Figure 1.0 FAIRCH**I**LD **Packaging Description:** Packaging Description: SOIC-8 parts are shipped in tape. The carrier tape is made from a dissipative (carbon filled) polycarbonate resin. The cover tape is a multilayer film (Heat Activated Adhesive in nature) primarily composed of polyester film, adhesive layer, sealant, and anti-static sprayed agent. These reeled parts in standard option are shipped with 2,500 units per 13° or 300cm diameter reel. The reels are dark blue in color and is made of polystyrene plastic (anti-static coated). Other option comes in 500 units per 7° or 177cm diameter reel. This and some other options are further described in the Packaging Information table. Antistatic Cover Tape ESD Label These full reles are individually barcode labeled and placed inside a standard intermediate box (illustrated in figure 1.0) made of recyclable corrugated brown paper. One box contains two reels maximum. And these boxes are placed inside a barcode labeled shipping box which comes in different sizes depending on the number of parts shipped. Static Dissipative Embossed Carrier Tape 63TNR Label Customized Label SOIC (8lds) Packaging Information Packaging Option Standard o flow code) L86Z D84Z **SOIC-8 Unit Orientation** Rail/Tube TNR Packaging type TNR TNR Qty per Reel/Tube/Bag 2.500 4.000 500 Reel Size 13" Dia 13" Dia 7" Dia Box Dimension (mm) 343y64y343 530x130x83 343y64y343 184v187v47 Max qty per Box 5,000 30,000 8,000 1,000 Weight per unit (gm) 0.0774 0.0774 0.0774 0.0774 Weight per Reel (kg) 0.6060 0.9696 0.1182 Note/Comments 343mm x 342mm x 64mm Standard Intermediate box ESD Label F63TNR Label sample F63TNI F63TN Label LOT: CBVK741B019 QTY: 2500 D/C1: D9842 D/C2: SOIC(8lds) Tape Leader and Trailer Configuration: Figure 2.0 0 0 0 0 0 0 0 $\bigcirc$ 0 Components Cover Tape Trailer Tape Leader Tape 1680mm minimum or 640mm minimum or 80 empty pockets 210 empty pockets

July 1999, Rev. B



July 1999, Rev. B

# SO-8 Tape and Reel Data and Package Dimensions, continued SOIC-8 (FS PKG Code S1) 1:1 Scale 1:1 on letter size paper Dimensions shown below are in: inches [millimeters] Part Weight per unit (gram): 0.0774 LEAD NO. IDENTIFICATION 0.0200 [0.51] 0.2260 [5.74] 0.0390 [0.99] 0.0500 [1.27] - 0.0500 [1.27] 0.010[0.25](M) [0.25] A CS B LAND PATTERN RECOMMENDATION GAGE PLANE 0.004[0.10] 3 0.0140 [0.36] ALL LEAD TIPS 1.27 TYP. ALL LEADS NOTES: UNLESS OTHERWISE SPECIFIED 1. STANDARD LEAD FINISH: 200 MICROINCHES / 5.08 MICRONS MINIMUM LEAD / TIN (SOLDER) ON COPPER. SO 0.150 WIDE 8 LEADS THESE DIMENSIONS DO NOT INCLUDE MOLD FLASH MAXIMUM LEAD 0.024 [0.609]

September 1998, Rev. A

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